

<b>Notice of References Cited</b>		Application/Control No. 10/518,948	Applicant(s)/Patent Under Reexamination DOU ET AL.	
		Examiner Mark Kopeć	Art Unit 1796	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A US-6,946,428	09-2005	Rey, Christopher Mark	505/237
	B US-			
	C US-			
	D US-			
	E US-			
	F US-			
	G US-			
	H US-			
	I US-			
	J US-			
	K US-			
	L US-			
	M US-			

**FOREIGN PATENT DOCUMENTS**

*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
N	WO 03/049208	06-2003	WO		
O					
P					
Q					
R					
S					
T					

**NON-PATENT DOCUMENTS**

*	Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
U	Cimberle et al "Magnetic characterization of sintered MgB <sub>2</sub> samples: effect of substitution or 'doping' with Li, Al and Si", Superconductor Science and Technology, 15(1) Jan 2002, pp 43-47.
V	He et al "Reactivity of MgB <sub>2</sub> with common substrate and electronic materials", Applied Physics Letters, 01/14/2002, Vol. 80 Issue 2, p291
W	Jiang et al "Stoichiometry dependence of the critical current density in pure and nano-SiC doped MgB <sub>2</sub> /Fe tapes", Physica C 451(Jan 2007) 71-76
X	Dou et al "Superconductivity, critical current density, and flux pinning in MgB <sub>2-x</sub> (SiC) <sub>x</sub> superconductor after SiC nanoparticle doping", Condensed Matter Superconductivity, 4 July 2002, 1-7.

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a))  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.